Amendments to the Claims:

The following listing replaces all prior listing of claims in the application.

Listing of Claims:

- (Currently amended) A method of fabricating a <u>stacked stackeded</u>
 structure comprising the following sequential steps:
- a) selecting a first plate and a second plate such that a portion of at least one of the first and second plates has a structured-surface having a roughness such that the surface is incapable of sticking to a surface of another plate,
- b) producing a sacrificial layer on at least a portion_part_of the surface of the first plate or the surface of the second plate, and
- c) bonding the first and second plates together, by bonding the sacrificial layer to a remaining first or second plate,

wherein the structured surface contacts the sacrificial layer
the method further comprising a step of at least partly eliminating
the sacrificial layer such that the portion at least partially faces the other plate.

2. – 4. (Cancelled)

- 5. (Currently amended) The method according to claim 4-claim 1 wherein selecting a first plate and a second plate further comprises selecting forming the structured-surface having a roughness by increasing the roughness of the selected first or second plate wherein the predetermined threshold is to greater than approximately 0.2 nm root-mean-square (RMS).
- 6. (Previously presented) The method according to claim 1 wherein selecting comprises selecting a least one of the plates that initially includes a surface layer.

- 7. ((Previously presented)) The method according to claim 6, wherein selecting further comprises selecting at least one of the plates wherein the surface layer comprises a monocrystalline surface layer.
- 8. (Previously presented) The method according to claim 6 wherein selecting further comprises selecting at least one of the plates wherein the surface layer comprises silicon.
 - 9. 10. (Cancelled)
- 11. (Currently amended) The method according to <u>claim 9 claim 1</u> wherein <u>further comprising forming the a surface layer comprising comprises</u> forming a layer of silicon nitride on one of the first or second plates.
- 12. (Previously presented) The method according to claim 1 further comprising smoothing at least one of a free surface of the sacrificial layer or a free surface of at least one of the plates before the bonding.
- 13. (Previously presented) The method according to claim 1 further comprising smoothing the free surface of the sacrificial layer and the free surface of at least one of the plates before the bonding.
- 14. (Previously presented) The method according to claim 1 wherein bonding comprises molecular bonding.
- 15. (Previously presented) The method according to claim 1 wherein bonding comprises bonding with a sacrificial bonding agent.
- 16. (Currently amended) The method according to claim 1 wherein bonding further comprises bonding assisted by at least one of a mechanical means, a plasma treatment, or a thermal treatment.
- 17. (Previously presented) The method according to claim 1 wherein the method further comprises applying a selected atmosphere before bonding.

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- 18. (Previously presented) The method according to claim 16 wherein assisting further comprises applying a selected atmosphere during bonding.
- 19. (Previously presented) The method according to claim 16 wherein bonding further comprises exposing the two plates to an open air environment before bonding.
- 20. (Previously presented) The method according to claim 16 wherein bonding further comprises bonding in an open air environment.
- 21. (Previously presented) The method according to claim 1 further comprising thinning at least one of the first or second plates after bonding.
- 22. (Previously presented) The method according to claim 1 wherein a major portion of at least one of the plates comprises a semiconductor material.
- 23. (Previously presented) The method according to claim 22 wherein the major portion comprises silicon.
- 24. (Previously presented) The method according to claim 1 wherein the sacrificial layer comprises silicon oxide.
- 25. (Previously presented) The method according to claim 1 wherein the sacrificial layer comprises a polymer.
- 26. (Currently amended) A <u>stacked stackeded structure</u> fabricated by a method according to claim 1.

27. – 41. (Cancelled)